

# Industrial Anomaly Detection and Localization Using Weakly-Supervised Residual Transformers

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arXiv:2306.03492v5 [cs.CV] 11 Jul 2024

**Abstract**—Recent advancements in industrial Anomaly Detection (AD) have shown that incorporating a few anomalous samples during training can significantly boost accuracy. However, this performance improvement comes at a high cost: extensive annotation efforts, which are often impractical in real-world applications. In this work, we propose a novel framework called “Weakly-supervised RESidual Transformer” (*WeakREST*), which aims to achieve high AD accuracy while minimizing the need for extensive annotations. First, we reformulate the pixel-wise anomaly localization task into a block-wise classification problem. By shifting the focus to block-wise level, we can drastically reduce the amount of required annotations without compromising on the accuracy of anomaly detection. Secondly, we design a residual-based transformer model, termed “Positional Fast Anomaly Residuals” (*PosFAR*), to classify the image blocks in real time. We further propose to label the anomalous regions using only bounding boxes or image tags as weaker labels, leading to a semi-supervised learning setting.

On the benchmark dataset MVTEC-AD, our proposed *WeakREST* framework achieves a remarkable Average Precision (AP) of 83.0%, significantly outperforming the previous best result of 75.8% in the unsupervised setting. In the supervised AD setting, *WeakREST* further improves performance, attaining an AP of 87.6% compared to the previous best of 78.6%. Notably, even when utilizing weaker labels based on bounding boxes, *WeakREST* surpasses recent leading methods that rely on pixel-wise supervision, achieving an AP of 87.1% against the prior best of 78.6% on MVTEC-AD. This precision advantage is also consistently observed on other well-known AD datasets, such as BTAD and KSDD2. Code is available at: [https://github.com/BeJane/Semi\\_REST](https://github.com/BeJane/Semi_REST)

**Index Terms**—Anomaly detection, Weakly supervised segmentation, Semi-supervised learning.

## I. INTRODUCTION

Product quality control is crucial in many manufacturing processes. Manual inspection is both costly and unreliable, especially given the limited time available for inspecting items on a continuously running assembly line. Consequently, automatic defect inspection is highly sought after in modern manufacturing industries [1]–[4]. With adequately supervised

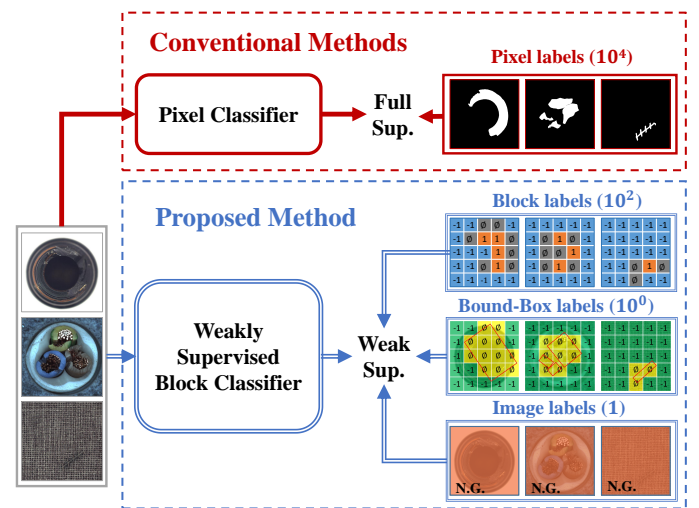


Fig. 1. The comparison between the proposed weak labels with the conventional paradigm. Different from the traditional pixel-wise labels (red box on the top), the proposed annotations can be divided into three levels, as shown in the three rows on the bottom blue box. Row-1: solving the AD problem as block-wise binary classifications with the normal samples, anomalous samples, and ignored ones shown in blue, orange, and gray respectively; Row-2: the weaker label based on bonding boxes which covering the entire anomalous region. Row-3: the weakest label using only tags indicating the defective status of the image. The numbers in the parenthesis denote the order of magnitudes (from  $10^4$  to 1) of the annotation clicks under the three levels of weak annotations. Best viewed in color.

training samples, defect detection can be effectively achieved using standard detection or segmentation algorithms [5]–[8]. However, in most practical scenarios, there are far fewer “anomalous” samples compared to normal ones, and the patterns of anomalies can vary significantly across different samples. To address this challenge, industrial defect detection is often framed as an Anomaly Detection (AD) problem [9], [10], using only normal instances for training. This approach, commonly referred to as the “unsupervised” setting, has garnered significant attention from the computer vision community.

The simplest method for implementing AD involves clas-

sifying normal image patches as one category and treating anomalous patches as outliers [11]–[17]. Some researchers propose localizing anomalies by comparing test image patches with normal references either directly taken from the training set [18]–[23] or reconstructed based on normal samples [24]–[28]. Additionally, distillation-based methods [29]–[32] and latent image registration [33], [34] have been proposed to enhance the detection of anomalies.

Despite the effectiveness of the prevailing unsupervised learning methods, some approaches [35]–[37] that train anomaly detectors in a supervised manner achieve higher performance. Traditional surface defect detection tasks [38]–[41] also rely on manually labeled defects. In practical settings, obtaining a few abnormal samples is often feasible, particularly during the “warming-up” stage of assembly lines, making this “supervised” approach typically valid.

In this paper, we address the limited time available for labeling newly obtained anomalous images. We propose a novel anomaly detection (AD) algorithm that combines high detection robustness with low annotation cost. The high-level concept of the proposed algorithm is illustrated in Fig 1. Specifically, we approach the AD task as a block-wise classification problem (as shown in the bottom right part of Fig 1), reducing the need to label thousands of anomalous pixels to just hundreds of anomaly blocks on a defective image. We introduce a faster and more effective residual generation algorithm called “Positional Fast Anomaly Residuals” (PosFAR), which generates features for each image block. These blocks are then classified as anomalous or normal using a Swin Transformer [42] model. Thanks to the innovative features and customized training scheme, our algorithm outperforms existing methods that require pixel-level supervision. Additionally, we propose a new foreground estimation method to further enhance AD performance when inspecting defects on objects.

Moreover, we propose to reduce annotation costs by labeling anomaly regions with only bounding boxes or even image tags. As shown in rows 3 and 4 on the right side of Fig 1, the bounding boxes cover all anomaly regions. The outside blocks (shown in green) can be directly used as normal samples in training. Meanwhile, the inside blocks (shown in yellow), labeled as “unknown,” can be effectively utilized through a novel semi-supervised learning algorithm tailored to our transformer-based anomaly detector. This productive use of unlabeled information allows our method to maintain high anomaly detection (AD) performance while using “cheaper” labels. The proposed algorithm termed “**Weakly-supervised RESidual Transformer**”, i.e., “**WeakREST**”, is validated on three benchmark datasets (MVTec-AD [9], BTAD [10] and KSDD2 [41]) under both the “unsupervised” and “supervised” setting to verify its superiority over the state-of-the-arts. Additionally, with only bounding-box annotations, WeakREST still outperforms all the state-of-the-art (SOTA) methods that are supervised by pixel labels.

The main contributions of this paper are summarised below.

- **Cheaper in terms of annotation:** From a practical standpoint, we argue that a more desirable property for AD algorithms, compared to “one-class” compatibility, is the efficient use of annotation information. To this end,

we propose several types of low-cost annotations: block-wise labels, bounding box labels, and image-level labels. To the best of our knowledge, this is the first time that block-wise labels are used for anomaly detection, and the use of bounding box labels and image tags is also innovative in the AD literature.

- **Better in terms of accuracy:** We developed the WeakREST algorithm based on a modified Swin-Transformer [42], a novel residual generation algorithm called “PosFAR”, and an effective foreground estimation algorithm for object-oriented AD tasks. Our proposed algorithm consistently surpasses state-of-the-art (SOTA) methods by significant margins across the three most recognized datasets and in all supervision conditions.
- **Cheaper and Better:** With the use of inexpensive bounding box or image-level labels, WeakREST can effectively leverage unlabeled features through our proposed ResMixMatch algorithm. This algorithm is inspired by MixMatch [43] but is highly customized for transformer models with residual inputs. Using these lightweight annotations, WeakREST still outperforms all competing SOTA methods trained with pixel-level labels.

The rest of this paper is organized as follows: Sec. II presents the recent work related to this paper. The proposed method is detailed in Sec. III. Extensive experiments are conducted in Sec. IV, and Sec. V concludes this paper.

## II. RELATED WORK

### A. Industrial Anomaly Detection

#### 1) Unsupervised Setting

In the conventional setting of industrial anomaly detection tasks, all the training samples are anomaly-free and the defective patterns are detected as outliers in the test phase [11]–[17], [44]–[48]. This setting is usually referred to as “unsupervised” in the AD literature even though mild supervision, *i.e.* the anomaly-free labels, still exist in the training set. To learn a discriminative model in this supervision condition, some sophisticated algorithms propose to generate artificial anomalous samples with synthetic defective regions [32], [49]–[51] for higher AD accuracy.

#### 2) Supervised Setting

Encouraged by the success of the AD models based on synthetic defects, some recently proposed methods [35]–[37] involve a few genuine anomalous samples to further unleash the discriminative power. They term this new setting as “supervised” in contrast to the default “unsupervised” setting. Note that in this supervision condition, the original anomaly-free samples as well as the fake defects are also employed in training.

In this work, we propose to replace the original pixel-level annotations with weak labels to reduce the annotation cost fundamentally. We term this supervision condition as “weakly-supervised” and design a novel algorithm for leveraging the weak labels to achieve even superior performance than the existing algorithms within the fully supervised condition.

### B. Path-Matching-based AD Algorithms

As a simple and typical example of the patch-matching-based AD methods, PatchCore algorithm [18] proposes the coreset-subsampling algorithm to build a “memory bank” of patch features, which are obtained via smoothing the neutral deep features pre-learned on ImageNet [52], [53]. The anomaly score is then calculated based on the Euclidean distance between the test patch feature and its nearest neighbor in the “memory bank”. Despite the simplicity, PatchCore performs dramatically well on the MVTEC-AD dataset [9].

The good performance of PatchCore encourages researchers to develop better variants based on it. The PAFM algorithm [19] applies patch-wise adaptive coreset sampling to improve the speed. [20] introduces the position and neighborhood information to refine the patch-feature comparison. Graphcore [23] utilizes graph representation to customize PatchCore for the few-shot setting. [21] modifies PatchCore by compressing the memory bank via k-means clustering. [22] combines PatchCore [18] and Defect GAN [54] for higher AD performances. Those variants, though achieving slightly better performances, all fail to notice the potential value of the intermediate information generated by the patch-matching. In this work, we use the matching residuals as the input tokens of our transformer model. The individual and the mutual information of the residuals are effectively exploited and new SOTA performances are then obtained.

### C. Swin Transformer for Anomaly Detection

As a variation of Vision Transformer (ViT) [55], Swin Transformer [42], [56] proposed a hierarchical Transformer with a shifted windowing scheme, which not only introduces several visual priors into Transformer but also reduces computation costs. Swin Transformer and its variants illustrate remarkable performances in various computer vision tasks, such as semantic segmentation [57]–[59], instance segmentation [60]–[62] and object detection [63]–[65].

In the realm of anomaly detection, some methods also employ Swin Transformer as the backbone network. [66] develops a hybrid structure decoder that combines convolution layers and the Swin Transformer. [67] improves the original shifted windowing scheme of the Swin Transformer for surface defect detection. Despite the success of Swin Transformer models in other domains, the Swin-Transformer-based AD algorithms could hardly outperform the SOTA methods on most acknowledged datasets such as [9], [10] and [41]. In this paper, we realised taming the Swin Transformer for the small training sets of AD problems by introducing a series of novel modifications.

### D. MixMatch and Weak Labels Based on Bounding Boxes

Semi-supervised Learning (SSL) is attractive since it saves massive labeling labor. Many efforts have been devoted to utilizing the information from the unlabeled data [43], [68]–[72], mainly focusing on the generation of high-quality pseudo labels. Inspired by the seminar work [73], [74] for data augmentation, MixMatch proposes a single-loss SSL method that

relies on a smart fusion process between labeled and unlabeled samples and thus enjoys high accuracy and simplicity.

In semantic segmentation, bounding boxes are usually used as weak supervision to save labeling costs. [75] exploits the tightness prior to the bounding boxes to generate the positive and negative bags for multiple instance learning (MIL). [76] integrates the tightness prior and a global background emptiness constraint derived from bounding box annotations into a weak semantic segmentation of medical images. [77] propose a bounding box attribution map (BBAM) to produce pseudo-ground-truth for weakly supervised semantic and instance segmentation.

In this work, within the block-wise classification framework, MixMatch is smartly tailored to exploit the information of unlabeled blocks which are brought by the weak supervision of bounding boxes. This combination of the novel semi-supervised learning scheme and the bounding box labels is remarkably effective according to the experiment results and also novel in the literature, to our best knowledge.

## III. OUR PROPOSED METHOD

### A. Overview of the Algorithm

The overall inference process of our WeakREST algorithm is illustrated in Fig 2. In general, the algorithm is based on the residual features of patch matching, so the model input contains the query (test) image and a set of reference images which are guaranteed to be defect-free. There are four stages in the whole process: the novel feature extracting stage and the residual feature (PosFAR) generation stage (the gray box and blue box), which are introduced in Sec. III-B; the defect classification process based on a Swin Transformer model (the orange box), which is defined in Sec. III-C and a post-process for foreground estimation (the green box) whose description can be found in Sec. III-E.

### B. PosFAR: Fast Anomaly Residuals with Position Constraints

1) *Matching Residual for Anomaly Detection*: Mathematically, for an input image  $I \in \mathbb{R}^{h_1 \times w_1 \times 3}$ , one can extract deep features as

$$[\mathbf{f}_1, \mathbf{f}_2, \dots, \mathbf{f}_M] \leftarrow \text{Flatten} \leftarrow \mathbf{F} = \Psi_{\text{CNN}}(I) \quad (1)$$

where  $\Psi_{\text{CNN}}(\cdot)$  represents a deep network, which is pre-trained on a large but neutral dataset (ImageNet [53] for example);  $\mathbf{F} \in \mathbb{R}^{h_f \times w_f \times d_f}$  denotes the generated deep feature tensor with  $M$  feature vectors ( $M = h_f \cdot w_f$ );  $\mathbf{f}_i \in \mathbb{R}^{d_f}$ ,  $i = 1, 2, \dots, M$  stands for the  $i$ -th deep feature vector extracted from the tensor  $\mathbf{F}$ . One then can build the memory “bank” of the defect-free training set as

$$\mathcal{B}_{raw} = \{\mathbf{f}_{i,j}^{ref} \in \mathbb{R}^{d_f} \mid \forall j = 1, \dots, N_{trn}, \forall i = 1, \dots, M\} \quad (2)$$

where  $N_{trn}$  denotes the number of training images.  $\mathcal{B}_{raw}$  contains  $M \cdot N_{trn}$  feature vectors and is usually further down-sampled as

$$\mathcal{B} = \Psi_{\text{core}}(\mathcal{B}_{raw}) = \{\mathbf{f}_t^{ref} \in \mathbb{R}^{d_f} \mid \forall t = 1, \dots, T\} \quad (3)$$

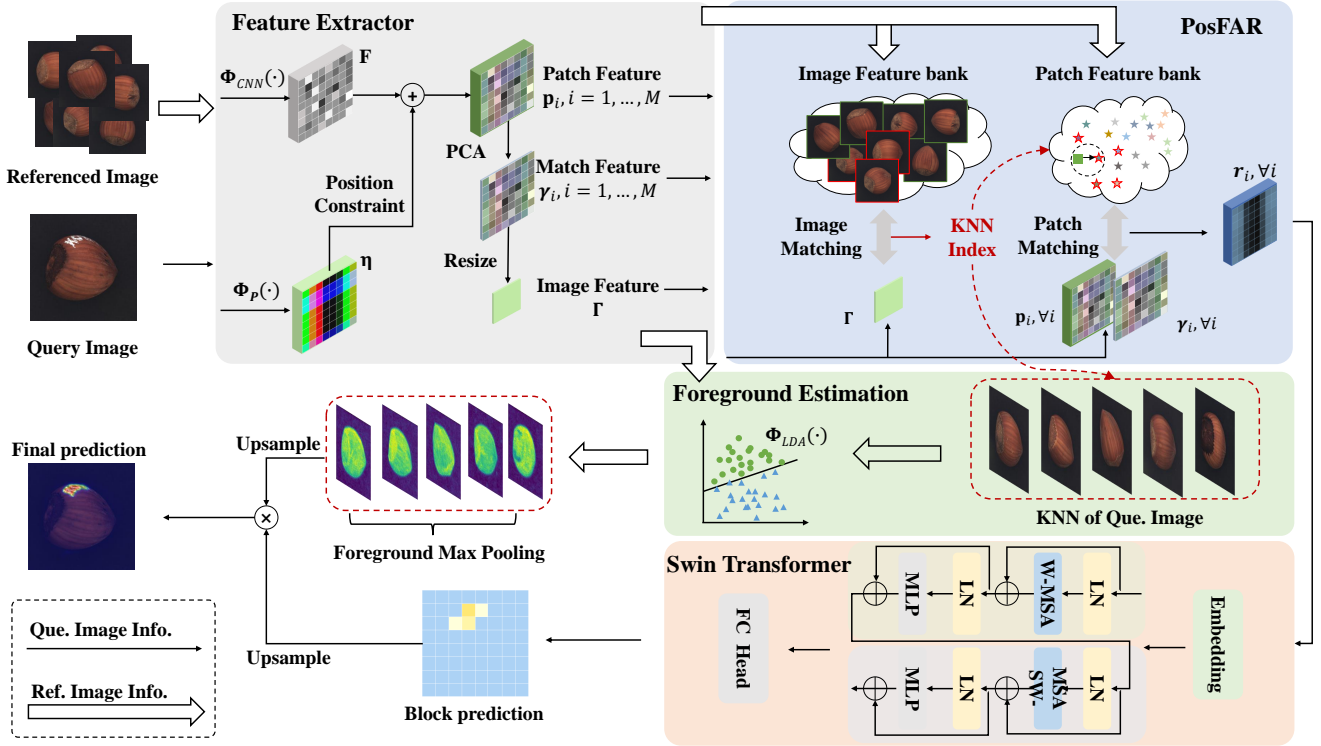


Fig. 2. The overview of the inference process of WeakREST. There are four modules of the proposed method: the novel feature extracting method (see Sec. III-B); the PosFAR residual generator (see Sec. III-B); the Swin Transformer module for block-wise anomaly classification (see Sec. III-C) and the foreground estimation module (see Sec. III-E). In this residual-based AD algorithm, the query and reference information are manipulated cooperatively in the entire process.

where  $\Psi_{\text{core}}(\cdot)$  represents the “coreset” sampling scheme proposed in [18], and  $T \ll M \cdot N_{\text{trn}}$  for decreasing the matching complexity. Then a test patch feature  $\mathbf{f}_i^{\text{tst}}$  is matched with the reference features in  $\mathcal{B}$  as

$$t^* = \arg \min_{\forall t=1, \dots, T} \|\mathbf{f}_i^{\text{tst}} - \mathbf{f}_t^{\text{ref}}\|_{l_2}. \quad (4)$$

The corresponding minimal distance  $d_i = \|\mathbf{f}_i^{\text{tst}} - \mathbf{f}_{t^*}^{\text{ref}}\|_{l_2}$  is usually used to calculate the anomaly score of the test patch [18]–[21]. However, this vanilla version of patch matching suffers some drawbacks, such as serious but unnecessary information loss, low efficiency, and ignorance of patch locations. In this paper, we introduce an effective patch-matching scheme and term the yielded residual feature “**Positional Fast Anomaly Residuals**” (PosFAR).

2) *Position Constrained Features*: As shown in [20], [78], the positional information yielded by patch comparison could improve AD performance. Herein, we are inspired by the “positional embedding” concept in the Transformers [42], [55] for patch matching: the original patch features are aggregated with their positional features encoded in the Transformer way [79]. Mathematically, given a patch feature  $\mathbf{f}$  defined in Eq. 1, we generate its “position-constrained” version as

$$\mathbf{p} = \mathbf{f} + \lambda_P \boldsymbol{\eta} = \mathbf{f} + \lambda_P \Phi_P(r, c) \quad (5)$$

where  $\boldsymbol{\eta} = \Phi_P(r, c) \in \mathbb{R}^{d_f}$  is usually termed Position Code in the literature [79], with the row-column coordinate  $[r, c]$  of  $\mathbf{f}$  extracted from the feature tensor  $\mathbf{F} \in \mathbb{R}^{h_f \times w_f \times d_f}$ . The function  $\Phi_P(\cdot)$  denotes the positional embedding process that

calculates the  $k$ -th element of  $\boldsymbol{\eta}$  as

$$\eta_k = \begin{cases} \sin\left(\frac{c}{10000^{8k/d_f}}\right) & k \in [0, \frac{d_f}{4}) \\ \cos\left(\frac{c}{10000^{8(k-d_f/4)/d_f}}\right) & k \in [\frac{d_f}{4}, \frac{d_f}{2}) \\ \sin\left(\frac{r}{10000^{8(k-d_f/2)/d_f}}\right) & k \in [\frac{d_f}{2}, \frac{3d_f}{4}) \\ \cos\left(\frac{r}{10000^{8(k-3d_f/4)/d_f}}\right) & k \in [\frac{3d_f}{4}, d_f) \end{cases} \quad (6)$$

where  $k \in [1, d_f]$ ,  $r \in [1, h_f]$ ,  $c \in [1, w_f]$ . In this way, the whole patch feature matching process is constrained by the positional information and the new patch feature is termed “Position Constrained Feature” (PCF) in this work. The ablation study in Section IV-F verifies the merit of this constraint.

3) *Matching in a Lower Dimensional Space*: The conventional patch matching process is slow and thus can hardly be employed in practice. Consequently, we propose a novel algorithm to generate the anomaly residuals faster while maintaining their discriminative property. Firstly, the patch matching is performed in a lower-dimensional space. A Principle Component Analysis (PCA) is conducted over the PCFs extracted from the training set and then a PCF  $\mathbf{p} \in \mathbb{R}^{d_f}$  is mapped to an lower-dimensional space as

$$\boldsymbol{\gamma} = \Psi_{\text{PCA}}(\mathbf{p}) = W_{\text{PCA}}(\mathbf{p} - \boldsymbol{\mu}_{\text{PCA}}) \in \mathbb{R}^{d_l}, \quad (7)$$

where  $d_l \ll d_f$  denotes the lower dimension,  $W_{\text{PCA}} \in \mathbb{R}^{d_l \times d_f}$  and  $\boldsymbol{\mu}_{\text{PCA}} \in \mathbb{R}^{d_f}$  stand for the PCA mapping matrix and the mean feature vector respectively,  $\boldsymbol{\gamma} \in \mathbb{R}^{d_l}$  denotes the feature for faster patch matching. In this way, one can convert the bank



$\mathcal{B}$  defined in Eq. 3 into its position-constrained and lower-dimensional version as

$$\mathcal{B}_{raw} \xrightarrow{+\lambda_P \boldsymbol{\eta}} \mathcal{B}_{raw}^P \xrightarrow{\Psi_{core}(\cdot)} \mathcal{B}^P \xrightarrow{\Psi_{PCA}(\cdot)} \mathcal{B}_l^P. \quad (8)$$

where the operation “ $+\lambda_P \boldsymbol{\eta}_i$ ” stands for the generation of PCF, the yielded  $\mathcal{B}_l^P = \{\boldsymbol{\gamma}_t^{ref} \in \mathbb{R}^{d_l} \mid \forall t = 1, \dots, T\}$ . Then for the  $i$ -th ( $i \in [1, 2, \dots, h_f \cdot w_f]$ ) test patch, the patch matching can be performed faster in this lower-dimensional space as

$$t^* = \arg \min_{\forall t=1, \dots, T} \|\boldsymbol{\gamma}_i^{tst} - \boldsymbol{\gamma}_t^{ref}\|_{l_2}, \quad (9)$$

where  $\boldsymbol{\gamma}_i^{tst} = \Psi_{PCA}(\mathbf{p}_i^{tst})$  represents the lower-dimensional PCF of the test patch.

4) *Matching with Similar Reference Images*: Secondly, to further increase the matching speed, we propose to *match a test patch only with the reference patches which belong to the “similar” reference images*. To define the image similarity, let us generate the image feature of an image  $\mathbf{I}$  as

$$\begin{aligned} \mathbf{F} \in \mathbb{R}^{h_f \times w_f \times d_f} &\xrightarrow{+\lambda_P \boldsymbol{\eta}} \mathbf{P} \in \mathbb{R}^{h_f \times w_f \times d_f} \\ &\downarrow \Psi_{PCA}(\cdot) \\ \mathbf{F} \in \mathbb{R}^{h_l \times w_l \times d_l} &\xleftarrow{\text{resize}} \mathbf{P}_l \in \mathbb{R}^{h_f \times w_f \times d_l}, \end{aligned} \quad (10)$$

where  $\mathbf{F} = \Psi_{CNN}(\mathbf{I})$  as defined in Eq. 1,  $\mathbf{P}$  denotes the feature tensor containing  $h_f \cdot w_f$  PCFs, the “resize” operation indicates to reduce the width and height of the feature tensor via interpolation. Then the distance between the  $j$ -th ( $j \in [1, 2, \dots, N_{trn}]$ ) reference image  $\mathbf{I}_j^{ref}$  and the test image  $\mathbf{I}^{tst}$  writes

$$\delta_j = \Delta(\mathbf{I}^{tst}, \mathbf{I}_j^{ref}), \quad (11)$$

where  $\Delta(\cdot)$  denotes the “robust distance” function which consider the image distance as a summation of patch-pair distances and ignores some of the most distant patch-pairs. Given all the distances between  $\mathbf{I}^{tst}$  and the reference images storing in  $\{\delta_1, \delta_2, \dots, \delta_{N_{trn}}\}$ , the image indexes of  $\mathbf{I}^{tst}$ ’s “similar reference images” are defined as

$$\{\delta_1, \delta_2, \dots, \delta_{N_{trn}}\} \xrightarrow{K\text{-NN Indexes}} \mathcal{Q} = \{q_1, q_2, \dots, q_K\} \quad (12)$$

5) *The Generation of PosFAR*: Given a test image  $\mathbf{I}^{tst}$  and a set of defect-free training images  $\{\mathbf{I}_1^{ref}, \mathbf{I}_2^{ref}, \dots, \mathbf{I}_{N_{trn}}^{ref}\}$ , one can firstly generate the ordinary bank  $\mathcal{B}^P = \{\mathbf{p}_t^{ref} \in \mathbb{R}^{d_f} \mid \forall t = 1, \dots, T\}$  and the corresponding low-dimensional bank  $\mathcal{B}_l^P = \{\boldsymbol{\gamma}_t^{ref} \in \mathbb{R}^{d_l} \mid \forall t = 1, \dots, T\}$  as shown in Eq. 8. Meanwhile, the training image index of each element in  $\mathcal{B}^P$  are saved in the set  $\{j_1, j_2, \dots, j_T\}$ . The proposed faster patch matching then can be defined as

$$t^* = \arg \min_{\forall j_t \in \mathcal{Q}} \|\boldsymbol{\gamma}_i^{tst} - \boldsymbol{\gamma}_t^{ref}\|_{l_2}, \quad \forall i = 1, \dots, M, \quad (13)$$

where  $\mathcal{Q}$  denotes the  $K$ -NN indexes of  $\mathbf{I}^{tst}$  as defined in Eq. 12,  $\boldsymbol{\gamma}_i^{tst}$  stands for the lower-dimensional PCF feature of  $i$ -th patch in  $\mathbf{I}^{tst}$ .

Finally, the PosFAR feature of each test patch is calculated as

$$\mathbf{r}_i = \lceil \text{ABS}(\mathbf{p}_i^{tst} - \mathbf{p}_{t^*}^{ref}) \rceil^\theta \in \mathbb{R}^{d_f}, \quad \forall i, \quad (14)$$

where  $\text{ABS}(\cdot)$  denotes the function of absolute value,  $\lceil \cdot \rceil^\theta$

stands for the element-wise  $\theta$ -power operation which is introduced to emphasis the larger elements in the residual vector. Compared with the distance-based residuals [18]–[21], PosFAR stores much richer intermedia information of patch matching. Further, each  $\mathbf{r}_i$  represents an “image block” which will be recognized as defective or defect-free by using the swin transformer model introduced below.

### C. Train the Residual-based Swin Transformer for Block-wise Anomaly Detection

1) *Block-wise Anomaly Labels*: Encouraged by the successful pioneering work [18], [32], [36], [51], in this paper, a discriminative model is also employed to predict the anomaly score map for test images. In the conventional “unsupervised” setting (as described in Sec. II-A), pseudo defective regions are usually augmented and so that the segmentation model [18], [32], [36], [51] can be trained smoothly with the pixel-wise labels. However, considering that the PosFAR feature introduced above is block-wise, we thus propose to cast the original pixel-wise segmentation task into a block classification problem. Accordingly, the conventional pixel labels need to be converted into the block-wise ones.

Suppose that the pixel label map of an image  $\mathbf{I} \in \mathbb{R}^{h_1 \times w_1 \times 3}$  is denoted as  $\mathbf{Y}_1^* \in \mathbb{R}^{h_1 \times w_1}$ , with 0 indicating defect-free pixels while 1 stands for the anomalous ones. We then can define our block-wise label map  $\mathbf{Y}_f^* \in \mathbb{R}^{h_f \times w_f}$  as

$$\mathbf{Y}_f^*(r_f, c_f) = \begin{cases} 1 & \sum_{(r_1, c_1) \in \mathcal{U}_{r_f, c_f}} \mathbf{Y}_1^*(r_1, c_1) > \epsilon^+ \rho^2 \\ -1 & \sum_{(r_1, c_1) \in \mathcal{U}_{r_f, c_f}} \mathbf{Y}_1^*(r_1, c_1) < \epsilon^- \rho^2 \\ \emptyset & \text{otherwise} \end{cases} \quad (15)$$

where  $\mathcal{U}_{r_f, c_f}$  denotes the pixels belonging to the image block at coordinate  $[r_f, c_f]$ ;  $\rho = h_1/h_f = w_1/w_f$ ;  $\epsilon^+$  and  $\epsilon^-$  are the two predefined thresholds; when labeled as  $\emptyset$ , the block is ignored during training, as introduced in Sec. III-C2. Fig. 3 illustrates this block labeling scheme.

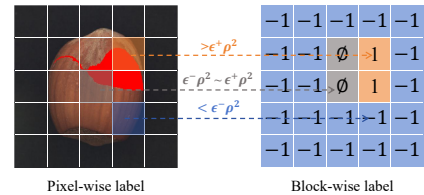


Fig. 3. The block labeling strategy employed in this work. The blocks with more than  $\epsilon^+ \rho^2$  anomaly pixels are labeled 1 (red) while those blocks with less than  $\epsilon^- \rho^2$  are labeled -1 (blue). The remaining blocks are labeled 0 and will be ignored in the training phase.

In this work, the block-wise labels are employed for the synthetic defects in the “unsupervised” setting as well as the genuine defects in the “supervised” setting. The experimental results of this work verify the superiority of this labeling strategy. On the other hand, in real-life AD tasks, one only needs to manually label image blocks rather than pixels and thus significant reduction on annotation cost is achieved.

2) *Swin Transformer with Focal Loss*: We convert the AD task into a block-wise binary classification problem and solve it by using a Swin Transformer model [42]. In specific, given a test image  $\mathbf{I}^{tst} \in \mathbb{R}^{h_I \times w_I \times 3}$ , its PosFARs  $\mathbf{r}_i \in \mathbb{R}^{d_f}, \forall i$  are calculated via Eq. 14 then fed into the Swin Transformer model as the input tokens [42], [55].

To suit the relatively small training sets in most anomaly detection challenges [9], [10], we design our Swin Transformer model with low complexity. As shown in Fig. 2, a linear embedding layer is first applied to the PosFAR features, projecting them into a 1024-dimensional space. Subsequently, 4 Swin Transformer blocks are employed to realize a 32-head self-attention within  $8 \times 8$  regular windows (W-MSA) and shifted windows (SW-MSA). Finally, the tokens with each representing an image block is classified as normal or anomalous via a fully connected layer. In mathematics, we have

$$p_+^i = \Psi_{\text{Swin}}(\mathbf{r}_i), \quad \forall i \in [1, 2, \dots, M], \quad (16)$$

where  $p_+^i \in [0, 1]$  denotes the normalized anomaly confidence (of the  $i$ -th token) predicted by the Swin Transformer model  $\Psi_{\text{Swin}}(\cdot)$

Considering that the normal image blocks usually dominate the original data distribution, we employ the focal loss [80] to lift the importance of the anomaly class. The focal loss used in this work writes:

$$\begin{aligned} \mathcal{L}_F = & -\frac{1}{|\mathcal{Z}^-|} \sum_{i \in \mathcal{Z}^-} \left[ (1 - \alpha) p_+^i{}^\gamma \log(1 - p_+^i) \right] \\ & -\frac{1}{|\mathcal{Z}^+|} \sum_{i \in \mathcal{Z}^+} \left[ \alpha (1 - p_+^i)^\gamma \log(p_+^i) \right] \end{aligned} \quad (17)$$

where  $\mathcal{Z}^+$  and  $\mathcal{Z}^-$  stands for the training sample sets (here are transformer tokens) corresponding to defective (+) and defect-free (-) classes respectively.

3) *Randomly Masked Residuals*: Different from the vanilla vision transformers [42], [55], [56], the input to our model is essentially *feature residual vectors*. Most conventional data augmentation methods [74], [81], [82] designed for images can not be directly used in the current situation. By contrast, inspired by the recently proposed MAE algorithm [79], we design a simple but effective feature augmentation approach termed “Randomly Masked Residuals” for achieving higher generalization capacity. In specific, when training, each tokens  $\{\mathbf{r}_1, \mathbf{r}_2, \dots, \mathbf{r}_M\}$  defined in Eq. 14 is randomly “masked” or “noised” as

$$\forall i, \mathbf{r}_i = \begin{cases} \mathbf{0}^T \in \mathbb{R}^{d_i} & \tau \in [0, \beta] \\ \mathbf{r}_i + \kappa \frac{\|\mathbf{r}_i\|_{l_2}}{\|\mathbf{g}\|_{l_2}} \mathbf{g} & \tau \in (\beta, 1] \end{cases} \quad (18)$$

where  $\tau$  is a random variable sampled from the uniform distribution  $[0, 1]$ ;  $\beta$  is the constant controlling the frequency of the reset operation;  $\mathbf{g} \in \mathbb{R}^{d_f}$  denotes a Gaussian noise vector;  $\kappa \in [0, 1]$  is a small constant for residual jittering. We found this augmentation approach can effectively increase the final performance of the proposed method, as shown in Sec. IV-F.

4) *Off-the-shelf methods for generating fake anomalies*: In the “unsupervised” setting of AD tasks, one needs to generate

fake anomalies to train a discriminative model properly. In this work, we follow the off-the-shelf fake/simulated anomaly generation approach proposed in the MemSeg algorithm [51]. Readers are recommended to the original work [51] for more details. Note that we also employ this anomaly generation method for the supervised and weakly-supervised settings to increase the variation of the training samples.

5) *Inference of the Swin Transformer*: Given  $\{p_+^1, p_+^2, \dots, p_+^M\}$  standing for the anomaly confidences of image blocks predicted by the Swin Transformer model  $\Psi_{\text{Swin}}(\cdot)$ , one can obtain the image-size anomaly map  $\mathbf{P}_+^* \in \mathbb{R}^{h_I \times w_I}$  as

$$\{p_+^1, \dots, p_+^M\} \xrightarrow{\text{reshape}} \mathbf{P}_+ \in \mathbb{R}^{h_f \times w_f} \xrightarrow{\text{upsample}} \mathbf{P}_+^* \quad (19)$$

#### D. Exploiting the Unlabeled Information via ResMixMatch

1) *The Weaker Labels with Trivial Labeling Cost*: To further reduce the annotation cost, we introduce three types of anomaly labels which are even “cheaper” than the block-wise ones. As depicted in Fig. 4. the proposed weak labels include the “rotated bounding-boxes” (left), the “axis-aligned bounding-boxes” (middle) and the “image-level labels” (right). From the figure we can see that the bounding box labels are the minimal rectangles covering the whole defective region, with or without rotation. On the other hand, the image-level label just represents the defective status of the image. These weak labels only requires the annotators input a few (1 to 4) clicks on the image.

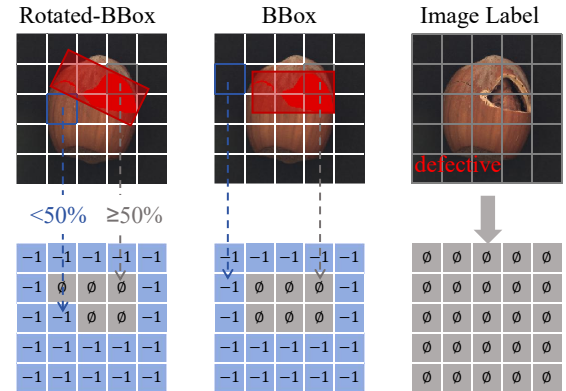


Fig. 4. The three types of weak labels employed in this work. From left to right: the “rotated bounding-boxes” (left), the “axis-aligned bounding-boxes” (middle) and the “image-level labels” (right). The lower part of each column illustrates the block-wise label converting operation for the associated weak label.

In the block-based framework of this work, one needs to convert the weaker labels into the block-wise annotations for model training. The lower part of Fig. 4 illustrates the label converting processes for the three kinds of weak labels. In a nutshell, for the bounding-box-based labels, we consider the outside blocks (overlapping ratio greater than 50%) of the bounding boxes as normal while the inside blocks (overlapping ratio less than 50%) are treated as “unknown”. In contrast, all the blocks of a image labeled as defective are unknown.

Note that the proposed weak labels are partially inspired by the pioneering works [38], [41] that also employ bounding boxes to annotate defective parts. However, our labeling

strategy is less misleading and the unknown region can be successfully exploited by the semi-supervised learning scheme introduced below.

2) *Exploiting the Unlabeled Blocks in a Semi-Supervised Manner*: The proposed weaker labels can achieve very efficient annotation processes. However, they arise another difficulty in training: An unignorable portion of the image blocks are unlabeled and no block is labeled as “defective”.

Fortunately, this semi-supervised situation is well studied in the machine learning literature [43], [68]–[71]. In this work, we borrow the high-level concept of the MixMatch method [43] into the learning process of a Swin Transformer model. The novel semi-supervised learning algorithm, termed “ResMixMatch”, is summarized in Algorithm 1.

From the algorithm we can see that, different from MixMatch [43] that treats every sample independently, in ResMixMatch, all the PosFAR features are related. The Swin Transformer model can effectively link the PosFARs from the same image via the self-attention mechanism and their anomaly confidences are then predicted depending on each other. The labels of the “unknown” blocks are estimated not only by the mixing-matching strategy but also based on the neighboring information. In this way, the “label guessing” becomes more confident.

### E. Foreground Region Estimation based on Coreset Sampling

Recent research on industrial anomaly detection [37], [51], [83] illustrates the performance gain by focusing on the foreground area in the object-oriented tasks. In this paper, we also follow this methodology to reduce the anomaly scores of uninterested background areas. However, instead of conducting the traditional image binarization, this work estimates the object region in a novel and more effective way.

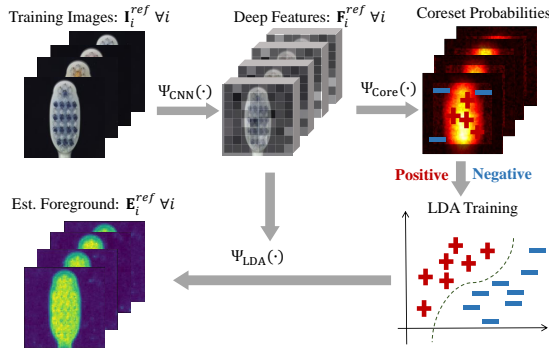


Fig. 5. The training and inference process of the coreset-based foreground estimation method proposed in this work. Note that as a prior constraint, the sampling ratio of positive (foreground) samples in the image boundaries is reduced.

In practice, we observe that the “coreset” algorithm (Eq. 3) employed in PatchCore [18] and inherited by this paper samples the foreground patches much more frequently than the background ones (see Fig. 5). This phenomenon mainly stems from the coreset’s preference to the “representatives” patterns in the raw bank. Considering that background regions of AD images usually contains much less pattern variations than the foreground parts, coreset will thus pay more attention to the foreground of the image.

### Algorithm 1 ResMixMatch training of WeakREST

- 1: **Input**: Swin Transformer model  $\Psi_{\text{Swin}}(\cdot)$ , PosFARs  $\mathbf{r}_i \in \mathbb{R}^{d_f}$ , the corresponding labels  $y_i^* \in \{-1, \emptyset(\text{unknown})\}$ ,  $i = 1, 2, \dots, M$ , sharpening temperature  $t$ , unlabeled loss weight  $\lambda_u$ , number of augmentations  $A$ , and focal loss parameters  $\{\alpha_x, \alpha_u, \gamma_x, \gamma_u\}$ .
- 2:  $A$ -Augmentation as Eq. 18
 
$$\forall i, \{\mathbf{r}_{i,j}, \forall j \mid j = 1, 2, \dots, A\} \leftarrow A\text{-Augmentation} \leftarrow \mathbf{r}_i$$

$$\forall i, \{y_{i,j}^*, \forall j \mid j = 1, 2, \dots, A\} \leftarrow \text{Copy} \leftarrow y_i^*$$
- 3: Guess pseudo labels through augmentation [43]
 
$$\forall i, \{\bar{y}_{i,j}, \forall j \mid j = 1, 2, \dots, A\} \leftarrow \text{Copy}$$

$$\leftarrow \text{Sharpen} \left( \frac{1}{A} \sum_{j=1}^A \Psi_{\text{Swin}}(\mathbf{r}_{i,j}), t \right)$$
- 4: Divide the tokens into labeled set  $\mathcal{X}$  and unlabeled set  $\mathcal{U}$  [43]
 
$$\mathcal{X} = \{X_i = \{\mathbf{r}_i, y_i^*\}, \forall i \mid y_i^* = -1\}$$

$$\mathcal{U} = \{U_i = \{\mathbf{r}_i, \bar{y}_i\}, \forall i \mid y_i^* = \emptyset\}$$
- 5: Combine the labeled and unlabeled tokens and shuffle
 
$$\mathcal{W} = \text{Shuffle}(\text{Union}(\mathcal{X}, \mathcal{U}))$$
- 6: Apply MixUp to all tokens [43]
 
$$\hat{\mathcal{X}} \leftarrow \{\text{MixUp}(X_i, W_i), \forall i \mid i = 1, \dots, |\mathcal{X}|\}$$

$$\hat{\mathcal{U}} \leftarrow \{\text{MixUp}(U_i, W_{i+|\mathcal{X}|}), \forall i \mid i = 1, \dots, |\mathcal{U}|\}$$
- 7: Randomly mask tokens as Eq. 18
 
$$\forall \{\hat{\mathbf{r}}_i, \hat{y}_i\} \in \text{Union}(\hat{\mathcal{X}}, \hat{\mathcal{U}}), \{\hat{\mathbf{r}}_i, \hat{y}_i\} = \text{RandomMask}(\hat{\mathbf{r}}_i, \hat{y}_i)$$
- 8: Classify the tokens
 
$$\forall i, p_+^i = \Psi_{\text{Swin}}(\hat{\mathbf{r}}_i)$$
- 9: Compute the labeled loss  $\mathcal{L}_x$  and unlabeled loss  $\mathcal{L}_u$ 

$$\mathcal{Z}_k^+ = \{\forall i \mid y_i^* = -1 \ \& \ \hat{y}_i > 0.5\}$$

$$\mathcal{Z}_u^+ = \{\forall i \mid y_i^* = \emptyset \ \& \ \hat{y}_i > 0.5\}$$

$$\mathcal{Z}_k^- = \{\forall i \mid y_i^* = -1 \ \& \ \hat{y}_i \leq 0.5\}$$

$$\mathcal{Z}_u^- = \{\forall i \mid y_i^* = \emptyset \ \& \ \hat{y}_i \leq 0.5\}$$

$$\mathcal{L}_x = -\frac{1}{|\mathcal{Z}_k^-|} \sum_{i \in \mathcal{Z}_k^-} \left[ (1 - \alpha_x) p_+^i \gamma_x \log(1 - p_+^i) \right]$$

$$- \frac{1}{|\mathcal{Z}_k^+|} \sum_{i \in \mathcal{Z}_k^+} \left[ \alpha_x (1 - p_+^i)^{\gamma_x} \log(p_+^i) \right]$$

$$\mathcal{L}_u = -\frac{1}{|\mathcal{Z}_u^-|} \sum_{i \in \mathcal{Z}_u^-} \left[ (1 - \alpha_u) p_+^i \gamma_u \log(1 - p_+^i) \right]$$

$$- \frac{1}{|\mathcal{Z}_u^+|} \sum_{i \in \mathcal{Z}_u^+} \left[ \alpha_u (1 - p_+^i)^{\gamma_u} \log(p_+^i) \right]$$
- 10: **Output**:  $\mathcal{L}_{mix} = \mathcal{L}_x + \lambda_u \mathcal{L}_u$

In this work, we propose to estimate the foreground region via binary classification. And the positive (foreground) training instances are sampled according to the sampling probability map of the coreset algorithm while the negative ones (background) are sampled based on the complement probability. The learned LDA model  $\Psi_{\text{LDA}}(\cdot)$  is fed with the CNN feature

$\mathbf{F} \in \mathbb{R}^{h_f \times w_f}$  (Eq. 1) and calculate foreground confidence map as  $\mathbf{E} = \Psi_{\text{LDA}}(\mathbf{F}) \in \mathbb{R}^{h_f \times w_f}$ . Fig. 5 depicts the foreground estimation process for the training images.

Finally, for a test image  $\mathbf{I}^{tst}$ , we reweight its anomaly map  $\mathbf{P}_+ \in \mathbb{R}^{h_f \times w_f}$  (Eq. 19) by the foreground information as

$$\tilde{\mathbf{P}}_+ = [\text{MaxPool}(\{\mathbf{E}_1^{ref}, \mathbf{E}_2^{ref}, \dots, \mathbf{E}_K^{ref}\})]^r \cdot \mathbf{P}_+, \quad (20)$$

where the set  $\{\mathbf{E}_1^{ref}, \mathbf{E}_2^{ref}, \dots, \mathbf{E}_K^{ref}\}$  stores the estimated foreground maps of  $\mathbf{I}^{tst}$ 's  $K$ -NN reference image, as introduced in Eq. 12, parameter  $r < 1$  is set to adjust the influence from the foreground estimation. In other words, *we do not directly infer the foreground region of the test image* as it might be broken due to the defect. In contrast, *we estimate the “rectified” foreground region of  $\mathbf{I}^{tst}$  with the “union” of the foreground regions of its neighboring reference images*. In the experiment of this paper, the proposed foreground estimation method illustrates its superiority, in terms of both speed and accuracy.

### F. Implementation details

In this work, all images are resized to  $512 \times 512$ , and a Wide-ResNet-50 model [84] (pre-trained on ImageNet-1K [53]) is employed as  $\Psi_{\text{CNN}}(\cdot)$  to extract deep features. Feature maps from layers 1, 2, and 3 are combined to form  $d_f = 1024$  feature vectors, as described in [18]. From these, 10% are sampled to build the bank  $\mathcal{B}$ . The parameters  $\lambda_P = 0.03$  for texture categories and  $\lambda_P = 0.15$  for object categories are set to generate PCFs. Residual features at  $\theta = 1$  and  $\theta = 2$  are concatenated and pooled to maintain the original dimension. Additionally, features from layer 1 of  $\Psi_{\text{CNN}}(\cdot)$  are applied to attain  $K = 64$  nearest images (see Eq. 12), while features from layer 2 are exploited to conduct foreground region estimation with  $r = 0.15$  for object categories (see Eq. 20).

The Swin model is trained using the AdamW optimizer with a weight decay of 0.05, a learning rate of  $5 \times 10^{-5}$ , and an Exponential Moving Average (EMA) decay of 0.999. Models are trained from scratch in an unsupervised setting or with block labels. Unsupervised models are used to initialize weights with ResMixMatch 1, applying a sharpening temperature of  $t = 0.5$  and linearly ramping up the unlabeled loss weight to  $\lambda_u = 5$  over the first 400 steps of training, following the MixMatch algorithm [43]. The parameters of the focal loss  $\alpha_x$ ,  $\alpha_u$ ,  $\gamma_x$ , and  $\gamma_u$  are set to 0.25, 0.75, 4, and 4, respectively.

To compare the final prediction map with the ground-truth label map, it is first upsampled to the same size as the ground-truth via bilinear interpolation and then smoothed using a Gaussian kernel of 4, as done in [18].

## IV. EXPERIMENTS

### A. Experiment Setting

In this section, extensive experiments are carried out to evaluate the proposed method, compared with a comprehensive collection of SOTA methods including DRAEM [50], RD [30], SSPCAB [85], DMAD [34], SimpleNet [86], DeSTSeg [32], PyramidFlow [47], CFLOW [78], RD++ [87], PRN [36], BGAD [37], DevNet [88], DRA [35], RealNet [83] and AHL

[89]. Considering the conceptual similarity in methodology, we also involve a SOTA method of weakly supervised segmentation, *i.e.* BoxTeacher [90], in the comparison to illustrate the practical advantage of WeakREST. The comparison is conducted on three well-acknowledged benchmarks, namely, the MVTec-AD [9] dataset, the BTAD [10] dataset and the KolektorSDD2 dataset [41], respectively. The involved AD algorithms are measured comprehensively by four popular threshold-independent metrics: Image-AUROC, Pixel-AUROC, PRO [91] (Per Region Overlap) and AP [50] (Average Precision). The first one focus on the precision of image-level anomaly detection while the latter three measure the performance of anomaly localization.

We perform all the experiments in both the unsupervised and supervised settings. In the unsupervised scenario, only normal data can be accessed during training but synthetic defects are artificially generated with pixel-wise labels. As to the supervised AD tasks, we randomly draw 10 anomalous images with various types of defects to the train set and remove them from the test set. This operation strictly follows the data splitting principle in [36] and [35]. In supervised experiments, the WeakREST model is firstly pretrained in the unsupervised condition and then fine-tuned using the genuine defective samples. The required block-wise labels of our methods are converted by using the method introduced in Sec. III-C1 (for pixel labels) and Sec. III-D1 (for bounding-box and image-level labels). All the experiments are conducted on a PC with a Intel i5-13450 CPU, 64G RAM and an NVIDIA RTX4090 GPU.

### B. Results on MVTec-AD

MVTec-AD [9] is the most popular AD dataset with 5,354 high-resolution color images belonging to 5 texture categories and 10 object categories. Each category contains a training set with only normal images and a test set with various kinds of defects as well as defect-free images. We conduct the experiments on this dataset within both unsupervised and supervised conditions.

The unsupervised AD results of the comparing algorithms on MVTec-AD [9] are shown in Table I. As shown in the table, our method achieves the highest average AP, average PRO and average pixel AUROC for both texture and object categories and outperforms the unsupervised SOTA by 7.2%, 1.7% and 0.4% respectively. Specifically, WeakREST ranks first on 93% (14 out of 15) categories with AP metric and the “first-ranking” ratios for the PRO and Pixel-AUROC are 53% and 67%. As to image-level metric image-AUROC, our method also achieves the highest accuracy (99.6%) which evens the performances of SimpleNet [86] and RealNet [83].

In addition, Table II illustrates that, trained with genuine defective samples, the WeakREST model still ranks first for the average AD performance evaluated by using all three metrics. In particular, our method outperforms the supervised SOTAs by 9.0% on AP, 0.7% on PRO and 0.5% on Pixel-AUROC. The “first-ranking” ratios of WeakREST in the supervised scenario are 93%, 80% and 93% one AP, PRO and Pixel-AUROC respectively. Similar to the unsupervised scenario,



Method	PatchCore [18] (CVPR2022)	DRAEM [50] (ICCV2021)	NFAD [37] (CVPR2023)	DMAD [34] (CVPR2023)	SimpleNet [86] (CVPR2023)	DeSTSeg [32] (CVPR2023)	PyramidFlow [47] (CVPR2023)	RD++ [87] (CVPR2023)	RealNet [83] (CVPR2024)	Ours
Carpet	64.1/95.1/99.1	53.5/92.9/95.5	<b>74.1/98.2/99.4</b>	63.8/95.9/99.0	44.1/92.0/97.7	72.8/~96.1	~97.2/97.4	~97.7/99.2	62.1/96.1/98.9	<b>81.6/98.3/99.4</b>
Grid	30.9/93.6/98.8	<b>65.7/98.3/99.7</b>	51.9/97.9/99.3	47.0/97.3/99.2	39.6/94.6/98.7	61.5/~99.1	~94.3/95.7	~97.7/99.3	59.2/96.9/99.5	<b>74.6/98.7/99.7</b>
Leather	45.9/97.2/99.3	75.3/97.4/98.6	70.1/99.4/99.7	53.1/98.0/99.4	48.0/97.5/99.2	<b>75.6/~99.7</b>	~99.2/98.7	~99.2/99.4	72.6/93.0/99.7	<b>79.9/99.5/99.8</b>
Tile	54.9/80.2/95.7	<b>92.3/98.2/99.2</b>	63.0/91.8/96.7	56.5/84.3/95.8	63.5/78.3/93.9	90.0/~98.0	~97.2/97.1	~92.4/96.6	92.2/93.7/99.1	<b>95.4/98.7/99.6</b>
Wood	50.0/88.3/95.0	77.7/90.3/96.4	62.9/95.6/96.9	45.5/89.3/94.8	48.8/83.9/93.9	<b>81.9/~97.7</b>	~97.9/97.0	~93.3/95.8	77.3/91.0/98.4	<b>84.7/97.1/98.2</b>
Average	49.2/90.9/97.6	72.9/95.4/97.9	64.4/96.6/98.4	53.2/93.0/97.6	48.8/89.3/96.7	<b>76.4/~98.1</b>	~97.2/97.2	~96.1/98.1	72.7/94.1/99.1	<b>83.2/98.5/99.3</b>
Bottle	77.7/94.7/98.5	86.5/96.8/99.1	77.9/96.6/98.9	79.6/96.4/98.8	73.0/91.5/98.0	<b>90.3/~99.2</b>	~95.5/97.8	~97.0/98.8	86.8/97.2/99.2	<b>93.6/97.8/99.5</b>
Cable	66.3/93.2/98.4	52.4/81.0/94.7	65.7/95.9/98.0	58.9/92.2/97.9	<b>69.3/89.7/97.5</b>	60.4/~97.3	~90.3/91.8	~93.9/98.4	54.3/91.1/97.6	<b>84.1/95.5/99.3</b>
Capsule	44.7/94.8/99.0	49.4/82.7/94.3	58.7/96.0/99.2	42.2/91.6/98.1	44.7/92.8/98.9	56.3/~99.1	~98.3/98.6	~96.4/98.8	59.1/90.5/99.3	<b>63.7/96.3/99.2</b>
Hazelnut	53.5/95.2/98.7	<b>92.9/98.5/99.7</b>	65.3/97.6/98.6	63.4/95.9/99.1	48.3/92.2/97.6	<b>88.4/~99.6</b>	~98.1/98.1	~96.3/99.2	80.5/92.9/99.5	<b>85.5/98.2/99.5</b>
Metal nut	86.9/94.0/98.3	<b>96.3/97.0/99.5</b>	76.6/94.9/97.7	79.0/94.2/97.1	92.6/91.3/98.7	93.5/~98.6	~91.4/97.2	~93.0/98.1	82.1/95.1/98.1	<b>98.3/98.1/99.8</b>
Pill	77.9/95.0/97.8	48.5/88.4/97.6	72.6/98.1/98.0	79.7/96.9/98.5	80.1/93.9/98.5	<b>83.1/~98.7</b>	~96.1/96.1	~97.0/98.3	80.7/90.0/99.0	<b>84.6/96.7/99.0</b>
Screw	36.1/97.1/99.5	58.2/95.0/97.6	47.4/96.3/99.2	47.9/96.5/99.3	38.8/95.2/99.2	<b>58.7/~98.5</b>	~99.8/99.7	~94.7/94.6	49.2/94.0/99.4	<b>67.1/97.3/99.5</b>
Toothbrush	38.3/89.4/98.6	44.7/85.6/98.1	38.8/92.3/98.7	71.4/91.5/99.3	51.7/88.7/98.6	<b>75.2/~99.3</b>	~97.9/98.5	~94.2/99.1	51.3/90.7/98.7	<b>80.8/97.2/99.7</b>
Transistor	66.4/92.4/96.3	50.7/70.4/90.9	56.0/82.0/94.0	58.5/85.2/94.1	69.0/93.2/96.8	64.8/~89.1	~94.7/96.9	~81.8/94.3	69.1/94.1/97.6	<b>82.5/95.3/97.2</b>
Zipper	62.8/95.8/98.9	<b>81.5/96.8/98.8</b>	56.0/95.7/98.6	50.1/93.8/97.9	60.0/91.2/97.8	<b>85.2/~99.1</b>	~95.4/96.6	~96.3/98.8	64.6/95.0/98.9	<b>89.1/98.7/99.7</b>
Average	61.1/94.2/98.4	66.1/89.2/97.0	61.5/94.5/98.1	63.1/93.4/98.0	62.7/92.0/98.2	<b>75.6/~97.9</b>	~95.2/96.6	~94.5/98.4	67.8/93.1/98.7	<b>82.9/97.1/99.2</b>
Total Average	57.1/93.1/98.1	68.4/91.3/97.3	62.5/95.2/98.2	59.8/93.3/97.9	58.1/91.1/97.7	<b>75.8/~97.9</b>	~95.9/96.8	~95.0/98.3	69.4/93.4/98.9	<b>83.0/97.6/99.3</b>
Image AUROC	99.1	98.0	97.4	<b>99.5</b>	<b>99.6</b>	98.6	~	99.4	<b>99.6</b>	<b>99.6</b>

TABLE I

THE COMPARISON OF THE AVERAGE PRECISION (AP), PER-REGION OVERLAP (PRO), PIXEL AUROC AND IMAGE AUROC METRICS UNDER UNSUPERVISED SETTING ON THE MVTEC-AD DATASET. THE BEST ACCURACY IN ONE COMPARISON WITH THE SAME DATA AND METRIC CONDITION IS SHOWN IN RED WHILE THE SECOND ONE IS SHOWN IN BLUE.

Method	PRN [36] (CVPR2023)	BGAD [37] (CVPR2023)	DevNet [88] (arXiv2021)	BoxTeacher [90] (CVPR2023)	DRA [35] (CVPR2022)	AHL [89] (CVPR2024)	Ours			
	Pixel	Pixel	Pixel	BBox	Image	Image	Block	RBBBox	BBox	Image
Carpet	82.0/97.0/99.0	83.2/98.9/99.6	45.7/85.8/97.2	78.3/96.4/99.2	52.3/92.2/98.2	~97.7	<b>88.4/99.1/99.7</b>	<b>88.6/99.1/99.8</b>	87.9/99.1/99.7	82.9/98.6/99.5
Grid	45.7/95.9/98.4	59.2/98.7/98.4	25.5/79.8/87.9	60.0/97.9/99.4	26.8/71.5/86.0	~97.7	<b>76.7/98.7/99.7</b>	<b>75.6/98.8/99.8</b>	74.0/98.7/99.7	75.1/98.6/99.7
Leather	69.7/99.2/99.7	75.5/99.5/99.8	8.1/88.5/94.2	56.2/97.3/98.6	5.6/84.0/93.8	~97.7	<b>85.7/99.6/99.9</b>	<b>84.1/99.6/99.9</b>	83.9/99.7/99.9	79.6/99.5/99.8
Tile	96.5/98.2/99.6	94.0/97.9/99.3	52.3/78.9/92.7	91.7/96.8/98.7	57.6/81.5/92.3	~97.7	97.4/99.2/99.8	<b>97.7/99.2/99.8</b>	<b>97.6/99.2/99.8</b>	96.9/99.1/99.7
Wood	82.6/95.9/97.8	78.7/96.8/98.0	25.1/75.4/86.4	67.4/93.4/96.2	22.7/69.7/82.9	~97.7	<b>90.7/98.5/99.3</b>	<b>90.8/98.6/99.3</b>	90.2/98.4/99.2	86.2/97.6/98.4
Average	75.3/97.2/98.9	78.1/98.4/99.2	31.3/81.7/91.7	70.7/96.4/98.4	33.0/79.8/90.6	~97.7	<b>87.8/99.0/99.7</b>	<b>87.3/99.1/99.7</b>	86.7/99.0/99.7	84.1/98.7/99.4
Bottle	92.3/97.0/99.4	87.1/97.1/99.3	51.5/83.5/93.9	82.7/92.0/97.2	41.2/77.7/69.1	~97.7	<b>93.6/98.3/99.6</b>	93.2/97.9/99.7	92.8/97.7/99.6	<b>93.8/98.1/99.6</b>
Cable	78.9/97.2/98.5	81.4/97.7/98.5	36.0/80.9/88.8	64.5/81.2/85.3	34.7/77.7/86.6	~97.7	<b>88.8/96.0/99.4</b>	<b>87.6/96.8/99.5</b>	87.1/96.5/99.5	84.5/95.5/99.3
Capsule	62.2/92.5/98.8	58.3/96.8/98.8	15.5/83.6/91.8	48.1/83.1/91.3	11.7/79.1/89.3	~97.7	<b>71.3/97.5/99.5</b>	<b>71.6/98.2/99.5</b>	68.7/97.9/99.4	66.8/97.2/99.4
Hazelnut	<b>93.8/97.4/99.7</b>	82.4/98.6/99.4	22.1/83.6/91.1	77.4/95.4/99.5	22.5/86.9/89.6	~97.7	86.9/98.8/99.7	87.6/99.0/99.6	86.3/98.8/99.6	<b>88.1/98.5/99.6</b>
Metal nut	98.0/95.8/99.7	97.3/96.8/99.6	35.6/76.9/77.8	88.6/79.2/97.4	29.9/76.7/79.5	~97.7	<b>99.3/98.2/99.9</b>	<b>98.9/98.3/99.9</b>	98.8/98.4/99.9	98.6/98.3/99.8
Pill	91.3/97.2/99.5	92.1/98.7/99.5	14.6/69.2/82.6	75.2/85.8/96.4	21.6/77.0/84.5	~97.7	93.4/97.8/99.7	<b>94.8/98.7/99.8</b>	<b>93.9/97.7/99.7</b>	88.7/97.3/99.5
Screw	44.9/92.4/97.5	55.3/96.8/99.3	1.4/31.1/60.3	35.3/56.8/79.6	5.0/30.1/54.0	~97.7	<b>71.8/98.1/99.7</b>	<b>71.5/98.2/99.7</b>	70.9/97.9/99.7	70.0/97.7/99.6
Toothbrush	78.1/95.6/99.6	71.3/96.4/99.5	6.7/33.5/84.6	41.0/72.5/94.6	4.5/56.1/75.5	~97.7	84.8/98.0/99.7	85.4/97.5/99.2	85.6/97.5/99.7	<b>85.5/97.6/99.7</b>
Transistor	85.6/94.8/98.4	82.3/97.1/97.9	6.4/39.1/56.0	32.1/52.8/70.8	11.0/49.0/79.1	~97.7	<b>94.0/99.0/99.6</b>	<b>88.5/98.7/99.2</b>	87.0/98.5/99.0	83.5/97.1/98.2
Zipper	77.6/95.5/98.8	78.2/97.7/99.3	19.6/81.3/93.7	73.9/96.8/99.0	42.9/91.0/96.9	~97.7	<b>91.5/99.1/99.8</b>	<b>90.4/98.9/99.7</b>	<b>90.4/98.9/99.7</b>	89.2/98.7/99.7
Average	80.3/95.5/99.0	78.6/97.4/99.1	20.9/66.3/82.1	61.9/79.6/91.1	22.5/70.1/82.6	~97.7	<b>87.5/98.1/99.6</b>	<b>87.0/98.2/99.6</b>	86.1/98.0/99.6	84.8/97.6/99.4
Total Average	78.6/96.1/99.0	78.4/97.7/99.2	24.4/71.4/85.3	64.8/85.2/93.5	26.0/73.3/85.3	~97.7	<b>87.6/98.4/99.7</b>	<b>87.1/98.5/99.7</b>	86.3/98.3/99.6	84.6/98.0/99.4
Image AUROC	99.4	99.3	94.5	83.4	95.9	97.0	<b>99.8</b>	<b>99.8</b>	<b>99.8</b>	<b>99.7</b>

TABLE II

THE COMPARISON OF THE AVERAGE PRECISION (AP), PER-REGION OVERLAP (PRO), PIXEL AUROC AND IMAGE AUROC METRICS FOR SUPERVISED AD ON THE MVTEC-AD DATASET. THE BEST ACCURACY IN ONE COMPARISON WITH THE SAME DATA AND METRIC CONDITION IS SHOWN IN RED WHILE THE SECOND ONE IS SHOWN IN BLUE.

the proposed method outperforms all the SOTA methods on Image-AUROC in the supervised setting. A new record of Image-AUROC 99.8% is obtained by WeakREST.

It is interesting to see that with only weak labels, WeakREST performances consistently better than the existing AD algorithm with full supervision. In particular, the WeakREST learned with image tags, which requires negligible annotation cost, beats all the SOTA methods with much more finer labels. The proposed algorithm illustrates remarkably high capacities of exploiting the information of unlabeled regions. Readers can also find the qualitative results of the proposed method compared with other SOTA algorithms in Fig. 7.

### C. Results on BTAD

As a more challenging alternative to MVTEC-AD, BTAD [10] (beanTech Anomaly Detection) contains 2,830 high-

resolution color images of three industrial products. Each product includes normal images in the train set and the corresponding test set consists of both defective and defect-free images.

We evaluate our algorithm on the BTAD dataset with those SOTA methods also reporting their results on this dataset. Table III shows that WeakREST achieves better performances to the unsupervised SOTA. The only exception occurs in the comparison on Image-AUROC where our method ranks the third (slightly worse than RealNet [83] and PyramidFlow [47]). Furthermore, as shown in Table IV, in the supervised condition, the proposed method surpasses SOTA methods by large margins: 9.7%, 4.5%, 0.6% and 1.8% on AP, PRO, Pixel-AUROC and Image-AUROC, respectively. Similar to the situation of MVTEC-AD, the weakly-supervised WeakREST models also obtains higher average performances than the fully-supervised SOTA algorithms.

Method	PatchCore [18] (CVPR2022)	DRAEM [50] (ICCV2021)	SSPCAB [85] (CVPR2022)	CFLOW [78] (WACV2022)	RD [30] (CVPR2022)	PyramidFlow [47] (CVPR2023)	NFAD [37] (CVPR2023)	RD++ [87] (CVPR2023)	RealNet [83] (CVPR2024)	Ours
01	47.1/78.4/96.5	17.0/61.4/91.5	18.1/62.8/92.4	39.6/60.1/94.8	49.3/72.8/95.7	~ ~/97.4	46.7/76.6/96.7	~ 73.2/96.2	<b>67.0/83.5/98.4</b>	<b>66.8/85.7/98.4</b>
02	56.3/54.0/94.9	23.3/39.0/73.4	15.8/28.6/65.6	65.5/56.9/93.9	<b>66.1/55.8/96.0</b>	~ ~/97.6	59.2/57.9/96.4	~ 71.3/96.4	54.3/49.1/95.9	<b>83.8/70.5/98.0</b>
03	51.2/96.4/99.2	17.2/84.3/96.3	5.0/71.0/92.4	<b>56.8/97.9/99.5</b>	45.1/98.8/99.0	~ ~/98.1	<b>62.8/98.8/99.7</b>	~ 87.4/99.7	54.7/90.0/99.6	<b>38.7/98.4/99.7</b>
Average	51.5/76.3/96.9	19.2/61.6/87.1	13.0/54.1/83.5	54.0/71.6/96.1	53.5/75.8/96.9	~ ~/97.7	56.2/77.8/97.6	~ 77.3/97.4	<b>58.7/74.2/98.0</b>	<b>63.1/84.9/98.7</b>
Image AUROC	92.6	89.0	88.3	90.5	94.3	<b>95.8</b>	94.6	95.6	<b>96.1</b>	94.4

TABLE III

RESULTS OF THE AP, PRO, PIXEL AUROC AND IMAGE AUROC METRICS UNDER UNSUPERVISED SETTING ON BTAD. THE BEST ACCURACY IN ONE COMPARISON WITH THE SAME DATA AND METRIC CONDITION IS SHOWN IN RED WHILE THE SECOND ONE IS SHOWN IN BLUE.

Method	PRN [36] (CVPR2023)	BGAD [37] (CVPR2023)	BoxTeacher [90] (CVPR2023)	Ours			
	Pixel	Pixel	BBox	Block	RBBox	BBox	Image
01	64.0/86.6/98.4	38.8/81.4/96.6	59.0/92.2/98.6	<b>84.7/94.0/99.4</b>	<b>79.0/89.8/99.1</b>	78.6/88.8/98.9	59.8/85.5/98.4
02	83.4/66.5/97.9	65.7/54.4/95.1	59.3/80.3/96.4	<b>87.8/78.9/98.5</b>	<b>85.7/74.1/98.3</b>	84.8/73.4/98.2	82.9/69.6/97.9
03	<b>77.4/99.5/99.9</b>	57.4/98.3/99.6	22.8/86.4/97.1	<b>81.2/99.6/99.9</b>	54.8/98.3/99.4	69.6/99.4/99.9	39.0/98.8/99.7
Average	74.9/84.2/98.7	54.0/78.0/97.1	47.0/86.3/97.3	<b>84.6/90.8/99.3</b>	73.2/87.4/98.9	<b>77.7/87.2/99.0</b>	60.6/84.7/98.7
Image AUROC	94.7	94.5	74.6	<b>96.5</b>	95.8	<b>96.0</b>	94.2

TABLE IV

RESULTS OF THE AP, PRO AND PIXEL AUROC AND IMAGE AUROC METRICS FOR SUPERVISED AD PERFORMANCE ON BTAD. THE BEST ACCURACY IN ONE COMPARISON WITH THE SAME DATA AND METRIC CONDITION IS SHOWN IN RED WHILE THE SECOND ONE IS SHOWN IN BLUE.

Method	Supervision	AP	PRO	P-AUROC	I-AUROC
PatchCore [18]	Un	<b>64.1</b>	88.8	97.1	94.6
DRAEM [50]	Un	39.1	67.9	85.6	81.1
SSPCAB [85]	Un	44.5	66.1	86.2	83.4
CFLOW [78]	Un	46.0	93.8	97.4	95.2
RD [30]	Un	43.5	<b>94.7</b>	<b>97.6</b>	<b>96.0</b>
Ours	Un	<b>76.9</b>	<b>98.5</b>	<b>99.7</b>	<b>96.1</b>
PRN [36]	Pixel	72.5	94.9	<b>97.6</b>	96.4
Box2Mask [92]	BBox	35.3	74.8	79.2	86.1
BoxTeacher [90]	BBox	23.2	79.3	90.9	74.9
Ours	Block	<b>77.7</b>	<b>99.0</b>	<b>99.7</b>	<b>97.9</b>
Ours	RBBox	76.9	<b>98.9</b>	<b>99.7</b>	97.5
Ours	BBox	76.4	98.8	<b>99.7</b>	97.6
Ours	Image	<b>77.0</b>	98.7	<b>99.7</b>	<b>97.7</b>

TABLE V

RESULTS OF ANOMALY LOCALIZATION PERFORMANCE ON KOLEKTORSDD2. THE BEST ACCURACY IN ONE COMPARISON WITH THE SAME DATA AND THE METRIC CONDITION IS SHOWN IN RED WHILE THE SECOND ONE IS SHOWN IN BLUE. NOTE THAT THE UPPER SUB-TABLE SHOWS THE RESULTS OBTAINED IN THE UNSUPERVISED CONDITION AND THE LOWER PART REPORTS THOSE WITH GENUINE DEFECTIVE SAMPLES.

#### D. Results on KolektorSDD2

KolektorSDD2 [41] dataset is designed for surface defect detection and includes various types of defects, such as scratches, minor spots, and surface imperfections. It comprises a training set with 246 positive (defective) and 2,085 negative (defect-free) images, as well as a test set with 110 positive and 894 negative images. We compare the performances of WeakREST with the SOTA results available in the literature.

As shown in Table V, the unsupervised WeakREST beats SOTA methods with a clear superiority (12.8%, 3.8%, 2.1% and 0.1% for AP, PRO, Pixel-AUROC and Image-AUROC, respectively). Under the supervised condition, our method also achieves better results and the WeakREST model supervised by image labels can already outperform existing methods with pixel-wise annotations.

$\epsilon^+$	$\epsilon^-$	Unsupervised	Weak-sup (RBBox)
0.25	0.00	82.8/97.5/99.2/99.5	<b>87.1/98.4/99.6/99.8</b>
0.50	0.10	<b>83.0/97.6/99.3/99.6</b>	<b>87.1/98.5/99.7/99.8</b>
0.75	0.20	82.4/97.6/99.3/99.6	86.8/98.5/99.6/99.8

TABLE VI

THE IMPACT OF THE BLOCK-LABEL THRESHOLDS (DEFINED IN EQ. 15). THE TEST IS PERFORMED ON MVTEC-AD USING AP, PRO, PIXEL-AUROC, AND IMAGE-AUROC METRICS IN BOTH UNSUPERVISED AND SUPERVISED SCENARIOS.

#### E. Analysis on weak labels

Recall that the main motivation of this work is to reduce the labeling cost of AD tasks, we report the annotation time-consumption of the proposed two weak labels compared with pixel-level annotations.

To obtain the labeling time, the pixel labels, block labels, bounding boxes and the image tags of anomalies on a subset of MVTEC-AD (10 defective images for each sub-category) are all manually annotated. Four master students majoring in computer vision completed the labeling task using the labeling tool proposed in this work.

The average annotation times of four kinds of labels are illustrated in Figure 6, along with the corresponding AD performances (Image-AUROC, Pixel-AUROC, PRO and AP). According to the figure, one requires only around 0.5 seconds to label a defective image. Besides, it takes around 5 seconds and 17 seconds to label bounding boxes and block-wise labels on an image, respectively. In contrast, the SOTA method [36] based on pixel labels needs more than 32 seconds for labeling one image, while yielding consistently lower accuracy.

Recall that our block-labels are all converted from the pixel-labels based on two pre-defined parameters  $\epsilon^+$  and  $\epsilon^-$  (Eq. 15), we carry out an experiment to verify the model robustness on the fluctuation of these parameters. As the results shown in Table VI, the AD accuracies of WeakREST are generally stable when  $\epsilon^+$  and  $\epsilon^-$  changes significantly.

Another concern about our weak labels might arise here

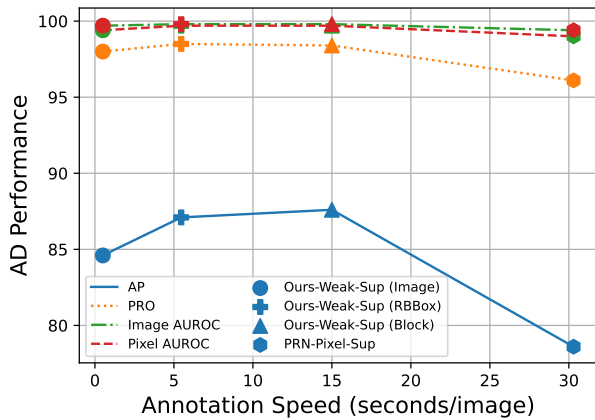


Fig. 6. The per-image annotation costs (x-axis) of the three levels of anomaly labels are shown as the circle (image label) plus (bounding-box label), triangle (block-wise label) and pentagon (pixel-wise label) shapes. The y-axis stands for the AD performances with the four metrics, shown as red-dashed (Pixel-AUROC), green-dashed (Image-AUROC), orange-dot (PRO) and blue-solid (AP) lines.

Perturb. (pixel)	RBBBox	BBox
0	87.1/98.5/99.7/99.8	86.3/98.3/99.6/99.8
-3 ~ +3	86.7/98.5/99.6/99.8	86.2/98.3/99.6/99.7
-5 ~ +5	86.8/98.5/99.6/99.8	85.3/98.2/99.6/99.8
-7 ~ +7	86.0/98.4/99.6/99.8	85.9/98.2/99.6/99.8

TABLE VII

BOUNDING-BOX LABEL PERTURBATION ANALYSIS. THE FIRST COLUMN DENOTES THE SCALES OF THE PERTURBATION THE TEST IS CONDUCTED ON MVTEC AD WITH AP, PRO, PIXEL-AUROC, AND IMAGE-AUROC METRICS.

is the proposed bounding-box labels are supposed to be annotated manually and thus the label noise is inevitable. In this sense, we test the proposed algorithm with perturbed bounding boxes and report the results in Table VII. From the table we can see that, even contaminated by the noise up to  $\pm 7$  pixels, which is around 15% of the average size of the bounding-boxes, the performance drop is still trivial: around 1% on AP while less than 0.2% for other metrics.

### F. Ablation study

In this section, the most influential modules of WeakREST are evaluated in the manner of an ablation study. The involved modules include: the usage of Swin Transformer model introduced in Sec. III-C2 (Swin); the Position Constrained Feature defined in Sec. III-B2 (PCF); the PCA for faster matching described in Sec. III-B3 (PCA); the filtering process for reference images introduced in Sec. III-B4 (Filter); the foreground estimation proposed in Sec. III-E (Fore); the ResMixMatch algorithm introduced in Sec. III-D (ResMix); the randomly masking (Mask) and residual jittering (Jitter) augmentation strategy defined in Sec. III-C3. From Table VIII we can see that most modules can improve the performance steadily except the “PCA” module which slightly reduce the AD performances. However, the accelerating module increase the running speed by around 28% (from 79.5 ms to 56.1 ms). The two accelerating module “PCA” and “Filter” can jointly double the algorithm speed while keeping the accuracy nearly unchanged.

In addition, the impact of the backbone selection over Swin Transformer [42], ViT [55] and the segmentation network employed in [32]) is illustrated in Table IX. One can see that the combination of Swin Transformer achieves the best scores while the ViT model performs worst in the unsupervised condition, probably due to the model overfitting to the synthetic defects. However, when genuine defective samples become available in training, ViT surpasses the segmentation network of DeSTSeg thanks to its higher capacity for feature extraction.

Finally, the performance of the proposed foreground estimation method (proposed in Sec. III-E) is evaluated in Table X, in terms of both accuracy and efficiency. From the table we can see that the proposed approach can almost consistently lift the AD scores, with a negligible additional complexity (0.3 ms). In contrast, to predict foreground regions directly on the test image will cost more computation (5.2 ms) while to treat the coresets sampling map (see Sec. III-E) as the foreground estimation can hardly increase the AD performances. When the traditional image binary method (employed in RealNet [83]) is used with WeakREST, the AD scores drop slightly.

## V. CONCLUSION

In this paper, we propose to solve the anomaly detection (AD) problem via block-wise classifications, which require significantly less annotation effort than pixel-wise segmentation. To achieve this, we designed a novel residual feature to represent the anomaly status of image blocks. We employ a Swin Transformer model, learned through a novel training strategy, to classify each block as defective or defect-free. The proposed two-stage algorithm achieves new state-of-the-art accuracy on three well-known AD datasets. Furthermore, when using weaker labels such as bounding boxes and image tags to roughly denote defective regions, our ResMixMatch learning scheme effectively exploits information from unlabeled regions, achieving AD performance close to that obtained with strong supervision. The proposed WeakREST algorithm sets record-breaking AD performance in the literature while requiring much coarser annotations. In short, our WeakREST is cheaper in annotation and better in accuracy.

This work paves a novel way to reduce annotation costs for AD problems while maintaining high accuracy. According to our experiments, the weakly-supervised setting proposed here seems a more practical alternative to the supervised setting that limits the number of training images. In the future, we anticipate the development of even better weakly-supervised AD algorithms by exploiting more useful information from unlabeled image regions.

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Setting	Module								Performance				
	Swin	PCF	PCA	Filter	Fore	ResMix	Masks	Jitter	AP	PRO	P-AUROC	I-AUROC	Latency (ms)
Un	✓								66.2	95.0	97.6	96.7	65.4
	✓	✓							79.5	96.8	98.6	99.3	79.1
	✓	✓	✓						82.8	<b>97.8</b>	<b>99.4</b>	99.5	79.5
	✓	✓	✓	✓					82.1	97.7	99.3	99.4	56.1
	✓	✓	✓	✓	✓				82.6	97.7	99.3	99.3	<b>39.4</b>
RBBBox	✓	✓	✓	✓	✓				83.1	97.6	99.3	99.7	39.7
	✓	✓	✓	✓	✓	✓			85.8	98.3	99.6	99.7	39.7
	✓	✓	✓	✓	✓	✓	✓		86.8	98.4	99.6	99.7	39.7
	✓	✓	✓	✓	✓	✓	✓	✓	<b>87.1</b>	<b>98.5</b>	<b>99.7</b>	<b>99.8</b>	39.7
	✓	✓	✓	✓	✓	✓	✓	✓	<b>87.1</b>	<b>98.5</b>	<b>99.7</b>	<b>99.8</b>	39.7

TABLE VIII  
ABLATION STUDY RESULTS ON MVTEC AD.

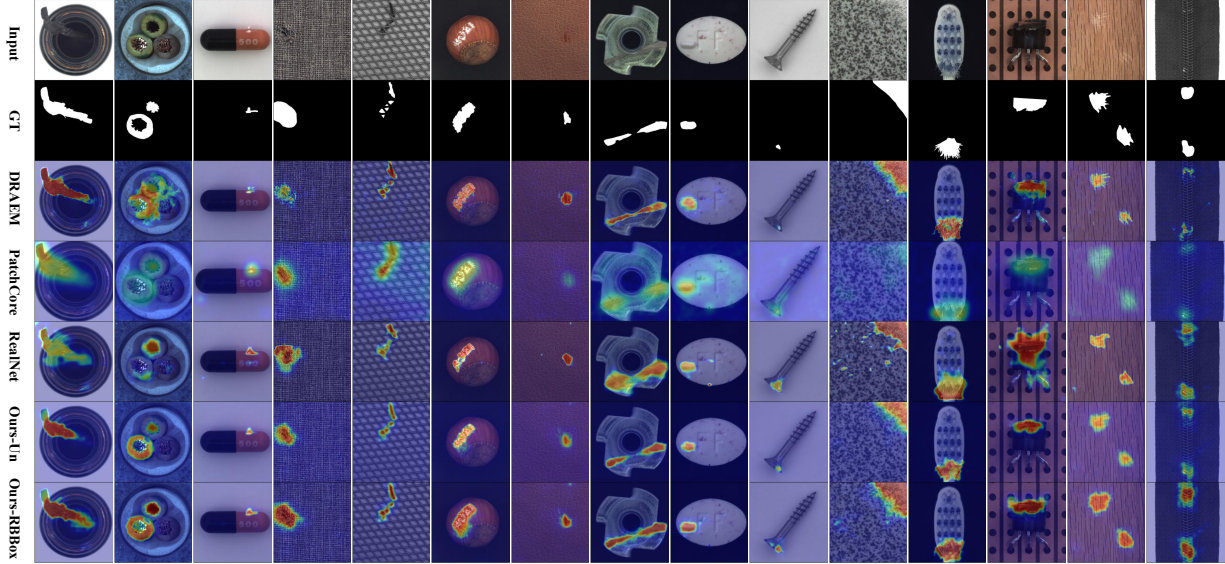


Fig. 7. Qualitative results of our WeakREST on MVTEC-AD, with the two levels of supervision: Un (unsupervised), Weak (RBBBox). Three unsupervised SOTA methods (RealNet [83], PatchCore [18] and DRAEM [50]) are also involved in the comparison.

Backbone	Unsupervised	Weak-sup (RBBBox)
Swin [42]	<b>83.0/97.6/99.3/99.6</b>	<b>87.1/98.5/99.7/99.8</b>
ViT [55]	75.7/94.0/98.5/99.3	80.5/96.8/99.0/99.3
DeSTSeg [32]	79.9/94.8/98.2/99.5	74.4/89.4/97.5/99.0

TABLE IX

EVALUATION ON BACKBONE SELECTION ON MVTEC AD ACROSS AP, PRO, PIXEL-AUROC, AND IMAGE-AUROC METRICS IN BOTH UNSUPERVISED AND WEAKLY-SUPERVISED SCENARIOS.

Foreground	Unsupervised	Weak-sup (RBBBox)	Latency (ms)
None	82.3/ <b>97.3/99.3/99.2</b>	86.4/ <b>98.2/99.6/99.5</b>	0
Ours	<b>83.0/97.2/99.3/99.6</b>	<b>87.0/98.2/99.6/99.8</b>	0.3
Ours (test image)	82.5/96.9/98.9/ <b>99.6</b>	86.6/ <b>98.2/99.6/99.8</b>	5.2
Coreset	82.3/96.6/99.0/99.5	86.4/ <b>98.2/99.6/99.8</b>	0.3
Binarization [83]	80.0/93.0/96.8/99.5	85.4/96.1/98.2/ <b>99.8</b>	0.4

TABLE X

COMPARING FOREGROUND ESTIMATION METHODS ON MVTEC AD (OBJECT CATEGORIES) ACROSS AP, PRO, PIXEL-AUROC, AND IMAGE-AUROC METRICS IN BOTH UNSUPERVISED AND WEAKLY-SUPERVISED SCENARIOS. NOTE THAT “NONE” STANDS FOR NO FOREGROUND INFORMATION IS USED. ALL THE METHODS GENERATE FOREGROUND MAPS AND THEN MERGED WITH THE RAW PREDICTION OF WEAKREST, AS DEFINED IN EQ. 20.

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